Abstracts

High-resolution electro-optic mapping of near-field distributions in integrated microwave circuits

K. Yang, G. David, S. Robertson, J.F. Whitaker and L.P.B. Katehi. "High-resolution electro-optic mapping of near-field distributions in integrated microwave circuits." 1998 MTT-S International Microwave Symposium Digest 98.2 (1998 Vol. II [MWSYM]): 949-952.

A field mapping system based on external electrooptic sampling has been developed in order to determine all components of the electric near-field distribution of guided microwaves with high spatial resolution. The capabilities of the setup are demonstrated by 2D-measurements of normal and tangential fields in a microwave distribution network.

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